

Notice of References Cited	Application/Control No. 10/099,988	Applicant(s)/Patent Under Reexamination HATTORI ET AL.	
	Examiner Khiem D Nguyen	Art Unit 2823	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,335,522	01-2002	Shimada et al.	250/201.3
*	B	US-6,408,122	06-2002	Shimada et al.	385/129
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP 8-15318	01-1996	Japan	Nobushi et al.	G01R 1/073
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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